◈IEEE

Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore
RELEASE 1.5

Welcome
United States Patent and Trademark Office

» Se

Help   FAQ   Terms   IEEE Peer Review | Quick Links ▾ |

Welcome to IEEE Xplore

○ Home
○ What Can
  I Access?
○ Log-out

Tables of Contents

○ Journals
  & Magazines
○ Conference
  Proceedings
○ Standards

Search

○ By Author
○ Basic
○ Advanced

Member Services

○ Join IEEE
○ Establish IEEE
  Web Account
○ Access the
  IEEE Member
  Digital Library

🖳 Print Format

Your search matched **653** of **966109** documents.

A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **descending** order.
You may refine your search by editing the current search expression or entering a new one the text box.
Then click **Search Again**.

| ((reliability)and (test)) and(monitoring) | Search Again |

Results:
Journal or Magazine = **JNL**   Conference = **CNF**   Standard = **STD**

1 **Reliability monitoring and screening issues with ultrathin gate dielect devices**
Abadeer, W.W.;
Device and Materials Reliability, IEEE Transactions on , Volume: 1 Issue: 1 , Ma
2001
Page(s): 60 -68

[Abstract]   [PDF Full-Text (216 KB)] **IEEE JNL**

2 **A test methodology to monitor and predict early life reliability failure mechanisms**
Conrad, T.R.; Mielnik, R.J.; Musolino, L.S.;
Reliability Physics Symposium 1988. 26th Annual Proceedings., International ,]
April 1988
Page(s): 126 -130

[Abstract]   [PDF Full-Text (256 KB)] **IEEE CNF**

3 **An in-process monitor for n-channel MOSFET hot carrier lifetimes**
Mistry, K.R.; Krakauer, D.B.; Doyle, B.S.; Spooner, T.A.; Jackson, D.B.;
Reliability Physics Symposium 1992. 30th Annual Proceedings., International , :
March-2 April 1992
Page(s): 116 -121

[Abstract]   [PDF Full-Text (480 KB)] **IEEE CNF**

4 **Condition monitoring of 11-132 kV cable accessories**

Dean, B.;
Ensuring the Reliability of 11-132 kV Cable Accessories (Digest No. 1998/191),
Colloquium on , 4 Feb. 1998
Page(s): 5/1 -5/4

[Abstract]   [PDF Full-Text (244 KB)] **IEE CNF**

5 Production implementation of a practical WLR program [wafer level reliability]
Garrard, S.;
Advanced Semiconductor Manufacturing Conference and Workshop. 1994. ASMC
Proceedings. IEEE/SEMI , 14-16 Nov. 1994
Page(s): 144 -146

[Abstract]   [PDF Full-Text (316 KB)] **IEEE CNF**

6 Isothermal wafer-level electromigration test for the characterization metal system reliability monitoring
Kuo, C.K.; Yuan, H.C.; Lee, S.C.; Lee, S.Y.; Chu, L.H.; Shiue, R.Y.; Yue, J.T.;
VLSI Technology, Systems, and Applications, 2001. Proceedings of Technical Pa
2001 International Symposium on , 18-20 April 2001
Page(s): 275 -278

[Abstract]   [PDF Full-Text (256 KB)] **IEEE CNF**

7 Condition monitoring of HV electrical rotating plant-on-line partial discharge techniques
Brown, A.J.;
Understanding your Condition Monitoring (Ref. No.1999/117), IEE Colloquium o
April 1999
Page(s): 1/1 -1/3

[Abstract]   [PDF Full-Text (96 KB)] **IEE CNF**

8 The practical side of thin dielectric monitoring and characterization
Suehle, J.S.; Messick, C.; Langley, B.;
Integrated Reliability Workshop, 1994. Final Report., 1994 International , 16-19
1994
Page(s): 1 -2

[Abstract]   [PDF Full-Text (128 KB)] **IEEE CNF**

9 **New control methods and process monitoring for improving performa of power diodes manufacturing**
Galateanu, L.; Bazu, M.; Tibeica, C.; Popa, E.; Nichita, A.; Turtudau, F.;
Semiconductor Conference, 2002. CAS 2002 Proceedings. International , Volum
8-12 Oct. 2002
Page(s): 347 -350 vol.2

[Abstract]   [PDF Full-Text (471 KB)] **IEEE CNF**

10 **Improvement of high voltage switchgear reliability**
Thuries, E.; Ebersohl, G.; Dupraz, J.P.; Chetay, O.; Moncorge, J.P.;
Trends in Distribution Switchgear, 1994., Fourth International Conference on , 7
Nov 1994
Page(s): 145 -149

[Abstract]   [PDF Full-Text (304 KB)] **IEE CNF**

11 **Demonstrated reliability of plastic-encapsulated microcircuits for mi applications**
Sun Man Tam;
Reliability, IEEE Transactions on , Volume: 44 Issue: 1 , March 1995
Page(s): 8 -13

[Abstract]   [PDF Full-Text (508 KB)] **IEEE JNL**

12 **On-line monitoring of power generating systems**
Kotlica, M.U.;
Power Station Maintenance - Profitability Through Reliability, 1998. First IEE/IM
International Conference on (Conf. Publ. No. 452) , 30 March-1 April 1998
Page(s): 32 -38

[Abstract]   [PDF Full-Text (804 KB)] **IEE CNF**

13 **A test vehicle for monitoring and improvement of CMOS reliability performance**
Remmerie, G.;
Euro ASIC '90 , 29 May-1 June 1990
Page(s): 444 -448

[Abstract]   [PDF Full-Text (376 KB)] **IEEE CNF**

14 An expert management system for VRLA batteries in remote telecommunications centers
Poulin, J.; Heron, R.; Mailloux, D.;
Telecommunications Energy Conference, 1994. INTELEC '94., 16th Internationa
Oct.-3 Nov. 1994
Page(s): 497 -504

[Abstract]   [PDF Full-Text (384 KB)] **IEEE CNF**

15 Investigation of the intrinsic SiO$_2$ area dependence using TDDB testi
Prendergast, J.; Finucane, N.; Suehle, J.;
Integrated Reliability Workshop Final Report, 1997 IEEE International , 13-16 O
1997
Page(s): 22 -25

[Abstract]   [PDF Full-Text (240 KB)] **IEEE CNF**

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search
Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting
No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

◈IEEE

Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE Xplore®
RELEASE 1.5

Welcome
United States Patent and Trademark Office

Help   FAQ   Terms   IEEE Peer Review | Quick Links   ▾| » Se

Welcome to IEEE Xplore®

○ Home
○ What Can
   I Access?
○ Log-out

Tables of Contents

○ Journals
   & Magazines
○ Conference
   Proceedings
○ Standards

Search

○ By Author
○ Basic
○ Advanced

Member Services

○ Join IEEE
○ Establish IEEE
   Web Account
○ Access the
   IEEE Member
   Digital Library

🖶 Print Format

Your search matched **583** of **966109** documents.

A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **descending** order.
You may refine your search by editing the current search expression or entering a new one the text box.
Then click **Search Again**.

(self <in> ti)and (test <in> ti) and interrupt | Search Again |

Results:
Journal or Magazine = **JNL**   Conference = **CNF**   Standard = **STD**

---

1 **A highly portable, self-stimulating and self-testing reliability test chip**
ASIC products
Erhart, D.L.; Colunga, T.; Lopez, D.;
ASIC Conference and Exhibit, 1993. Proceedings., Sixth Annual IEEE Internation
Sept.-1 Oct. 1993
Page(s): 160 -163

[Abstract]   [PDF Full-Text (452 KB)] **IEEE CNF**

---

2 **Mixed-signal custom IC control processors incorporating design for**
test/self-test
Grout, I.A.; Burge, S.E.; Winsby, A.J.;
DSP Chips in Real Time Measurement and Control (Digest No: 1997/301), IEE
Colloquium on , 25 Sept. 1997
Page(s): 1/1 -1/4

[Abstract]   [PDF Full-Text (388 KB)] **IEE CNF**

---

3 **Self-tuning predictive control of a hydraulic test rig**
Daley, S.; Liu, G.P.;
Adaptive Controllers in Practice '97 (Digest No: 1997/176), IEE Colloquium on ,
April 1997
Page(s): 12/1 -12/3

[Abstract]   [PDF Full-Text (192 KB)] **IEE CNF**

---

4 **The "Prometeo" test bed: a unidirectional WDM transparent self heali**

ring in a field environment
Merli, S.; Arecco, F.; Mariconda, A.; Pozzi, F.; Veghini, F.; Iannone, E.;
Integrated Optics and Optical Fibre Communications, 11th International Confere
on, and 23rd European Conference on Optical Communications (Conf. Publ. No.:
448) , Volume: 3 , 22-25 Sept. 1997
Page(s): 347 -350 vol.3

[Abstract]   [PDF Full-Text (436 KB)] **IEE CNF**

5 The development and application of intelligent self test concepts in reconfigurable modular avionic systems
Cooper, R.; Shark, L.K.; Terrell, T.J.;
Systems Design for Testability, IEE Colloquium on , 26 Apr 1995
Page(s): 8/1 -8/5

[Abstract]   [PDF Full-Text (228 KB)] **IEE CNF**

6 Incorporating boundary-scan and built-in self-test within a VHDL-bas ASIC design cycle
Findlay, P.; Dickinson, B.; Harriss, M.;
Testing-the Gordian Knot of VLSI Design, IEE Colloquium on , 28 May 1993
Page(s): 3/1 -3/4

[Abstract]   [PDF Full-Text (216 KB)] **IEE CNF**

7 Progress in the long term testing of an all dielectric self supporting cɛ for power system use
Carlton, G.; Carter, C.N.; Peacock, A.J.;
Electricity Distribution, 1993. CIRED., 12th International Conference on , 17-21
1993
Page(s): 3.16/1 -3.16/4 vol.3

[Abstract]   [PDF Full-Text (228 KB)] **IEE CNF**

8 Self-testing in an electricity meter: new contribution to intelligent metering
Rozman, M.; Jeglic, A.; Jamnik, P.;
Metering Apparatus and Tariffs for Electricity Supply, 1992., Seventh Internatioı
Conference on , 17-19 Nov 1992
Page(s): 161 -163

[Abstract]   [PDF Full-Text (120 KB)] **IEE CNF**

9 **Self-tuning controller design for a nonlinear engine testing dynamom**
King, P.J.; Burnham, K.J.; James, D.J.G.; Norton, J.; Sharpe, S.R.;
Real Control Problems - No Solutions Yet?, IEE Colloquium on , 30 May 1991
Page(s): 2/1 -2/4

[Abstract]   [PDF Full-Text (132 KB)] **IEE CNF**

10 **Implementation of a self-tuning controller to the dynamometer torqı**
loop of an engine test cell
King, P.J.; Burnham, K.J.; James, D.J.G.; Norton, J.; Sharpe, S.R.;
Control 1991. Control '91., International Conference on , 25-28 Mar 1991
Page(s): 110 -114 vol.1

[Abstract]   [PDF Full-Text (228 KB)] **IEE CNF**

11 **Aging and self-healing in connectors: implications for accelerated te:**
Williamson, J.B.P.;
Electrical Contacts, IEE Colloquium on , 4 Apr 1989
Page(s): 2/1

[Abstract]   [PDF Full-Text (40 KB)] **IEE CNF**

12 **Automatic self-test provides improved accuracy and user confidence**
Rudkin, A.M.;
Reliable Electronic Measurements, IEE Colloquium on , 10 Mar 1989
Page(s): 6/1 -6/4

[Abstract]   [PDF Full-Text (172 KB)] **IEE CNF**

13 **Propulsion and friction braking diagnostics and self test capabilities**
Roberts, R.D.;
Main Line Railway Electrification, 1989., International Conference on , 25-28 Se

Page(s): 63 -66

[Abstract]   [PDF Full-Text (336 KB)] **IEE CNF**

14 **The benefits of built in self test for OEM designers**
Diamond, P.; Bradford, J.;

Custom VLSI Design and Test, IEE Colloquium on , 31 Oct 1988
Page(s): 8/1 -8/9

[Abstract]   [PDF Full-Text (460 KB)] **IEE CNF**

15 **An integrated high-level test synthesis algorithm for built-in self-tes
designs**
Yang, L.T.; Muzio, J.;
Integrated Circuits and Systems Design, 2001, 14th Symposium on. , 10-15 Se
2001
Page(s): 115 -121

[Abstract]   [PDF Full-Text (616 KB)] **IEEE CNF**

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search
Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting
No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

◈IEEE

Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE Xplore®
RELEASE 1.5

Welcome
United States Patent and Trademark Office

Help   FAQ   Terms   IEEE Peer Review   Quick Links ▾   » Se

Welcome to IEEE Xplore

○ Home
○ What Can
   I Access?
○ Log-out

Tables of Contents

○ Journals
   & Magazines
○ Conference
   Proceedings
○ Standards

Search

○ By Author
○ Basic
○ Advanced

Member Services

○ Join IEEE
○ Establish IEEE
   Web Account

○ Access the
   IEEE Member
   Digital Library

🖳 Print Format

Your search matched **[0]** of **[966109]** documents.

You may refine your search by editing the current search expression or entering
a new one the text box. Then click search Again.

((self <in> ti)and (test <in> ti)) and(interrupt) | Search Again |

OR

Use your browser's back button to return to your original search page.

Results:

No documents matched your query.

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search
Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting
No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

◆IEEE

Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE Xplore
RELEASE 1.5

Welcome
United States Patent and Trademark Office

» Se

<u>Help</u>   <u>FAQ</u>   <u>Terms</u>   <u>IEEE Peer Review</u> |Quick Links   ▾|

Welcome to IEEE Xplore

○ Home
○ What Can
   I Access?
○ Log-out

Tables of Contents

○ Journals
   & Magazines
○ Conference
   Proceedings
○ Standards

Search

○ By Author
○ Basic
○ Advanced

Member Services

○ Join IEEE
○ Establish IEEE
   Web Account
○ Access the
   IEEE Member
   Digital Library

🖨 Print Format

Your search matched **26** of **966109** documents.

A maximum of **26** results are displayed, **15** to a page, sorted by **Relevance** in **descending** order.
You may refine your search by editing the current search expression or entering a new one the text box.
Then click **Search Again**.

|((self)and (test)) and(interrupt)| |Search Again|

Results:
Journal or Magazine = **JNL**   Conference = **CNF**   Standard = **STD**
_____

1 **A static fault current limiting and interrupting device**
Putrus, G.A.; Jenkins, N.; Cooper, C.B.;
Fault Current Limiters - A Look at Tomorrow, IEE Colloquium on , 8 Jun 1995
Page(s): 5/1 -5/6

[Abstract]   [PDF Full-Text (268 KB)] **IEE CNF**
_____

2 **IBM single chip RISC processor (RSC)**
Moore, C.R.; Balser, D.M.; Muhich, J.S.; East, R.E.;
Computer Design: VLSI in Computers and Processors, 1992. ICCD '92. Proceed
IEEE 1992 International Conference on , 11-14 Oct. 1992
Page(s): 200 -204

[Abstract]   [PDF Full-Text (420 KB)] **IEEE CNF**
_____

3 **Study on applications of two kinds of fluoride materials in SF$_6$ self-er arc quenching**
Yu Jianjun; Guo Wenyuan; Gao Liangyu;
Electrical Insulating Materials, 1995. International Symposium on , 17-20 Sept.
Page(s): 499 -502

[Abstract]   [PDF Full-Text (192 KB)] **IEEE CNF**
_____

4 **An efficient parallel transparent BIST method for multiple embedded memory buffers**
Huang, D.C.; Jone, W.B.; Das, S.R.;
VLSI Design, 2001. Fourteenth International Conference on , 3-7 Jan. 2001

Page(s): 379 -384

[Abstract]   [PDF Full-Text (488 KB)] **IEEE CNF**

5 Behaviour of SF$_6$ high-voltage circuit breakers with different arc-extinguishing systems at short-line fault switching
Knoblock, H.; Habedank, U.;
Science, Measurement and Technology, IEE Proceedings- , Volume: 148 Issue:
Nov. 2001
Page(s): 273 -279

[Abstract]   [PDF Full-Text (646 KB)] **IEE JNL**

6 A microcomputer-based speed controller for lift drives
Petrovcic, J.; Strmcnik, S.;
Industry Applications, IEEE Transactions on , Volume: 24 Issue: 3 , May-June
Page(s): 487 -498

[Abstract]   [PDF Full-Text (1028 KB)] **IEEE JNL**

7 Interruption ability of a self extinguishing type gas circuit breaker
Arita, H.; Natsui, K.; Tsukushi, M.; Kurosawa, Y.; Hirasawa, K.;
Power Delivery, IEEE Transactions on , Volume: 5 Issue: 3 , July 1990
Page(s): 1362 -1369

[Abstract]   [PDF Full-Text (556 KB)] **IEEE JNL**

8 Cathode spot dynamics on pure metals and composite materials in hi current vacuum arcs
Chaly, A.M.; Logatchev, A.A.; Shkol'nik, S.M.;
Plasma Science, IEEE Transactions on , Volume: 25 Issue: 4 , Aug. 1997
Page(s): 564 -570

[Abstract]   [PDF Full-Text (176 KB)] **IEEE JNL**

9 A parallel transparent BIST method for embedded memory arrays by tolerating redundant operations
Huang, D.C.; Jone, W.B.;
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions
Volume: 21 Issue: 5 , May 2002

Page(s): 617 -628

[Abstract]   [PDF Full-Text (352 KB)] **IEEE JNL**

10 **New vacuum arc control technology and its application**
Niwa, Y.; Nitta, K.; Yokokura, K.; Somei, H.; Kaneko, E.;
Power Engineering Society Winter Meeting, 2000. IEEE , Volume: 3 , 23-27 Jar

Page(s): 2111 -2116 vol.3

[Abstract]   [PDF Full-Text (468 KB)] **IEEE CNF**

11 **Dual processor VHSIC MIL-STD-1750 A computer module**
Coulon, K.;
Aerospace and Electronics Conference, 1988. NAECON 1988., Proceedings of th
1988 National , 23-27 May 1988
Page(s): 54 -59 vol.1

[Abstract]   [PDF Full-Text (600 KB)] **IEEE CNF**

12 **Secondary arc current interruption in an unconventional MV distribu
system: digital simulation and experimental test results**
Carrus, A.; Gatta, F.M.; Cinieri, E.;
Properties and Applications of Dielectric Materials, 1991., Proceedings of the 3r
International Conference on , 8-12 July 1991
Page(s): 354 -358 vol.1

[Abstract]   [PDF Full-Text (348 KB)] **IEEE CNF**

13 **Fault scanner for reconfigurable logic**
Shnidman, N.R.; Mangione-Smith, W.H.; Potkonjak, M.;
Advanced Research in VLSI, 1997. Proceedings., Seventeenth Conference on ,
Sept. 1997
Page(s): 238 -255

[Abstract]   [PDF Full-Text (912 KB)] **IEEE CNF**

14 **Dynamic fault tolerance in FPGAs via partial reconfiguration**
Emmert, J.; Stroud, C.; Skaggs, B.; Abramovici, M.;
Field-Programmable Custom Computing Machines, 2000 IEEE Symposium on ,
April 2000

Page(s): 165 -174

[Abstract]   [PDF Full-Text (972 KB)] **IEEE CNF**

15 **Self excitation of induction motors compensated by permanently
connected capacitors and recommendations for IEEE Std 141-1993**
Ermis, M.; Calir, Z.; Cadirci, I.; Zenginobuz, G.; Tezcan, H.;
Industry Applications Conference, 2000. Conference Record of the 2000 IEEE ,
Volume: 5 , 8-12 Oct. 2000
Page(s): 3135 -3145 vol.5

[Abstract]   [PDF Full-Text (808 KB)] **IEEE CNF**

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search
Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting
No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top